FCC Part 15C Measurement and Test Report

For

Santok Limited

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Ruislip, Middlesex, HA4 0EJ United Kingdom

FCC ID: 2AE7RSANTOKQ65

FCC Rule(s):	FCC Part 15.247		
Product Description:	Mobile Phone		
Tested Model:	<u>Q65</u>		
Report No.:	STR15068223I-2		
Tested Date:	2015-06-26 to 2015-07-08		
Issued Date:	<u>2015-07-08</u>	1 1. 11000	
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1. GENERAL INFORMATION

1.1 Product Description for Equipment Under Test (EUT)

Client Information	
Applicant:	Santok Limited
Address of applicant:	Santok House, Unit L, Braintree Industrial Estate, Braintree
	Road, South Ruislip, Middlesex, HA4 0EJ United Kingdom
Manufacturer:	GIPO HOLDINGS LIMITED
Address of manufacturer:	East 1201, Phase II, Hi-tech Plaza, Futian District,
	Shenzhen

General Description of EUT	
Product Name:	Mobile Phone
Brand Name:	Tecmobile
Model No.:	Q65
Adding Model:	Raspberry, Lychee, Storm 2, Sync 5S, Sync 5i, Sync 5.5
Hardware Version:	DR100-MB-V0.2
Software Version:	Q65_DS819_V0.0.2_150625
IMEI:	355386000145387/355386000145395
Rated Voltage:	DC 3.7V Li-ion Battery
Battery:	1500mAh
Power Adeptor	Q65
Power Adaptor:	Input: AC 100-240V Output: DC 5V/1000mA
Device Category:	Portable Device

The EUT is GSM850/900/DCS1800/PCS1900, WCDMA Band II, V, Mobile Phone. The Mobile Phone is intended for speech and Multimedia Message Service (MMS) transmission. It is equipped with GPRS/EGPRS class 12 for GSM850 and GSM1900 and Bluetooth, Wi-Fi, GPS and camera functions. For more information see the following datasheet

Note: The test data is gathered from a production sample provided by the manufacturer. The appearance of others models listed in the report is different from main-test model Q65, but the circuit and the electronic construction do not change, declared by the manufacturer.

Technical Characteristics of EUT	
Bluetooth Version:	V4.0(EDR mode)
Frequency Range:	2402-2480MHz
RF Output Power:	1.36dBm (Conducted)
Data Rate:	1Mbps, 2Mbps, 3Mbps
Modulation:	GFSK, Pi/4 QDPSK, 8DPSK
Quantity of Channels:	79
Channel Separation:	1MHz
Type of Antenna:	Integral Antenna
Antenna Gain:	1.9dBi
Lowest Internal Frequency of EUT:	32.768KHz

1.2 Test Standards

The following report is prepared on behalf of the Santok Limited in accordance with FCC Part 15, Subpart C, and section 15.203, 15.205, 15.207, 15.209 and 15.247 of the Federal Communication Commissions rules.

The objective is to determine compliance with FCC Part 15, Subpart C, and section 15.203, 15.205, 15.207, 15.209 and 15.247 of the Federal Communication Commissions rules.

Maintenance of compliance is the responsibility of the manufacturer. Any modification of the product, which result in lowering the emission, should be checked to ensure compliance has been maintained.

1.3 Test Methodology

All measurements contained in this report were conducted with ANSI C63.4-2009, American National Standard for Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the range of 9 kHz to 40 GHz. The measurement guide DA 00-705 for frequency hopping spread spectrum systems shall be performed also.

1.4 Test Facility

FCC – Registration No.: 934118

Shenzhen SEM.Test Technology Co., Ltd. EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files and the Registration is 934118.

Industry Canada (IC) Registration No.: 11464A

The 3m Semi-anechoic chamber of Shenzhen SEM.Test Technology Co., Ltd. has been registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 11464A.

CNAS Registration No.: L4062

Shenzhen SEM.Test Technology Co., Ltd. is a testing organization accredited by China National Accreditation Service for Conformity Assessment (CNAS) according to ISO/IEC 17025. The accreditation certificate number is L4062. All measurement facilities used to collect the measurement data are located at 1/F, Building A, Hongwei Industrial Park, Liuxian 2nd Road, Bao'an District, Shenzhen, P.R.C (518101).

CNAS Registration No.: L1659

CCIC Southern Electronic Product Testing (Shenzhen) Co., Ltd. is a testing organization accredited by China National Accreditation Service for Conformity Assessment (CNAS) according to ISO/IEC 17025. The accreditation certificate number is L1659. Some measurement facilities used to collect the measurement data are located at Building 28/29, Shigudong, Xili Industrial Area, Xili Street, Nanshan District, Shenzhen, Guangdong, China

1.5 EUT Setup and Test Mode

The EUT was operated in the engineering mode to fix the Tx frequency that was for the purpose of the measurements. All testing shall be performed under maximum output power condition, and to measure its highest possible emissions level, more detailed description as follows:

Test Mode L	Test Mode List				
Test Mode	Description	Remark			
TM1	Low Channel	2402MHz			
TM2	Middle Channel	2441MHz			
TM3	High Channel	2480MHz			
TM4	Hopping	2402-2480MHz			

Modulation Configure			
Modulation	Packet	Packet Type	Packet Size
	DH1	4	27
GFSK	DH3	11	183
	DH5	15	339
	2DH1	20	54
Pi/4 DQPSK	2DH3	26	367
	2DH5	30	679
	3DH1	24	83
8DPSK	3DH3	27	552
	3DH5	31	1021

Normal mode: the Bluetooth has been tested on the modulation of GFSK, (Pi/4)DQPSK and 8DPSK, compliance test and record the worst case.

EUT Cable List and Details			
Cable Description	Length (m)	Shielded/Unshielded	With / Without Ferrite
Earphone Cable	1.2	Unshielded	Without Core
USB Cable	1.0	Shielded	Without Core

Special Cable List and Details				
Cable Description	Length (m)	Shielded/Unshielded	With / Without Ferrite	
/	/	/	/	

Auxiliary Equipment List and Details			
Description	Manufacturer	Model	Serial Number
Notebook	Lenovo	E10	LR-63C8R

2. SUMMARY OF TEST RESULTS

FCC Rules	Description of Test Item	Result
§ 2.1093	RF Exposure	Compliant
§ 15.203; § 15.247(b)(4)(i)	Antenna Requirement	Compliant
§15.205	Restricted Band of Operation	Compliant
§ 15.207(a)	Conducted Emission	Compliant
§ 15.209(a)	Radiated Spurious Emissions	Compliant
§ 15.247(a)(1)(iii)	Quantity of Hopping Channel	Compliant
§ 15.247(a)(1)	Channel Separation	Compliant
§ 15.247(a)(1)(iii)	Time of Occupancy (Dwell time)	Compliant
§ 15.247(a)	20dB Bandwidth	Compliant
§ 15.247(b)(1)	RF Power Output	Compliant
§ 15.247(d)	Band Edge (Out of Band Emissions)	Compliant
§ 15.247(a)(1)	Frequency Hopping Sequence	Compliant
§ 15.247(g), (h)	Frequency Hopping System	Compliant

N/A: not applicable

3. RF Exposure

3.1 Standard Applicable

According to § 1.1307 and § 2.1093, the portable transmitter must comply the RF exposure requirements.

3.2 Test Result

This product complied with the requirement of the RF exposure, please see the SAR Report.

4. Antenna Requirement

4.1 Standard Applicable

According to FCC Part 15.203, an intentional radiator shall be designed to ensure that no antenna other than that furnished by the responsible party shall be used with the device. The use of a permanently attached antenna or of an antenna that uses a unique coupling to the intentional radiator shall be considered sufficient to comply with the provisions of this section.

4.2 Evaluation Information

This product has an integral antenna, fulfill the requirement of this section.

5. Frequency Hopping System Requirements

5.1 Standard Applicable

According to FCC Part 15.247(a)(1), The system shall hop to channel frequencies that are selected at the system hopping rate from a pseudo randomly ordered list of hopping frequencies. Each frequency must be used equally on the average by each transmitter. The system receivers shall have input bandwidths that match the hopping channel bandwidths of their corresponding transmitters and shall shift frequencies in synchronization with the transmitted signals.

(g) Frequency hopping spread spectrum systems are not required to employ all available hopping channels during each transmission. However, the system, consisting of both the transmitter and the receiver, must be designed to comply with all of the regulations in this section should the transmitter be presented with a continuous data (or information) stream. In addition, a system employing short transmission bursts must comply with the definition of a frequency hopping system and must distribute its transmissions over the minimum number of hopping channels specified in this section.

(h) The incorporation of intelligence within a frequency hopping spread spectrum system that permits the system to recognize other users within the spectrum band so that it individually and independently chooses and adapts its hopsets to avoid hopping on occupied channels is permitted. The coordination of frequency hopping systems in any other manner for the express purpose of avoiding the simultaneous occupancy of individual hopping frequencies by multiple transmitters is not permitted.

5.2 Frequency Hopping System

This transmitter device is frequency hopping device, and complies with FCC part 15.247 rule.

This device uses Bluetooth radio which operates in 2400-2483.5 MHz band. Bluetooth uses a radio technology called frequency-hopping spread spectrum, which chops up the data being sent and transmits chunks of it on up to 79 bands (1 MHz each; centred from 2402 to 2480 MHz) in the range 2,400-2,483.5 MHz. The transmitter switches hop frequencies 1,600 times per second to assure a high degree of data security. All Bluetooth devices participating in a given piconet are synchronized to the frequency-hopping channel for the piconet. The frequency hopping sequence is determined by the master's device address and the phase of the hopping sequence (the frequency to hop at a specific time) is determined by the master's internal clock. Therefore, all slaves in a piconet must know the master's device address and must synchronize their clocks with the master's clock.

Adaptive Frequency Hopping (AFH) was introduced in the Bluetooth specification to provide an effective way for a Bluetooth radio to counteract normal interference. AFH identifies "bad" channels, where either other wireless devices are interfering with the Bluetooth signal or the Bluetooth signal is interfering with another device. The AFH-enabled Bluetooth device will then communicate with other devices within its piconet to share details of any identified bad channels. The devices will then switch to alternative available "good" channels, away from the areas of interference, thus having no impact on the bandwidth used.

This device was tested with an bluetooth system receiver to check that the device maintained hopping synchronization, and the device complied with these requirements for DA 00-705 and FCC Part 15.247 rule.

5.3 EUT Pseudorandom Frequency Hopping Sequence

Pseudorandom Frequency Hopping Sequence Table as below:

Channel: 08, 24, 40, 56, 40, 56, 72, 09, 01, 09, 33, 41, 33, 41, 65, 73, 53, 69, 06, 22, 04, 20, 36, 52, 38, 46, 70, 78, 68, 76, 21, 29, 10, 26, 42, 58, 44, 60, 76, 13, 03, 11, 35, 43, 37, 45, 69, 77, 55, 71, 08, 24, 08, 24, 40, 56, 40, 48, 72, 01, 72, 01, 25, 33, 12, 28, 44, 60, 42, 58, 74, 11, 05, 13, 37, 45 etc.

The system receiver have input bandwidths that match the hopping channel bandwidths of their corresponding transmitters and shift frequencies in synchronization with the transmitted signals.

6. Quantity of Hopping Channels and Channel Separation

6.1 Standard Applicable

According to FCC 15.247(a)(1), frequency hopping systems operating in the 2400-2483.5 MHz band may have hopping channel carrier frequencies that are separated by 25 kHz or two-thirds of the 20 dB bandwidth of the hopping channel, and frequency hopping systems in the 2400-2483.5 MHz band shall use at least 15 channels.

6.2 Test Equipment List and Details

Description	Manufacturer	Model	Serial Number	Cal. Date	Due. Date
Spectrum Analyzer	Agilent	E4402B	US41192821	2015-05-28	2016-05-27
Attenuator	ATTEN	ATS100-4-20	/	2015-05-28	2016-05-27

6.3 Test Procedure

According to the DA 00-705, the number of hopping frequencies test method as follows.

Remove the antenna from the EUT and then connect a low loss RF cable from the antenna port to the spectrum analyzer.

Set span = the frequency band of operation (2400MHz to 2483.5MHz) RBW = 100kHz, VBW = 100kHz Sweep = auto Detector function = peak Trace = max hold Allow the trace to stabilize, observed the band of 2400MHz to 2483.5MHz, than count it out the number of channels for comparing with the FCC rules.

The channel spacing test method as follows:

Set span = wide enough to capture the peaks of two adjacent channels

Resolution (or IF) Bandwidth (RBW) $\geq 1\%$ of the span

Video (or Average) Bandwidth (VBW) \geq RBW

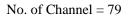
Sweep = auto; Detector function = peak; Trace = max hold

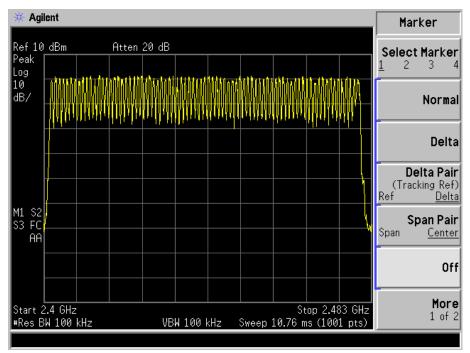
Allow the trace to stabilize. Use the marker-delta function to determine the separation between the peaks of the adjacent channels. The limit is specified in one of the subparagraphs of this Section. Submit this plot.

6.4 Environmental Conditions

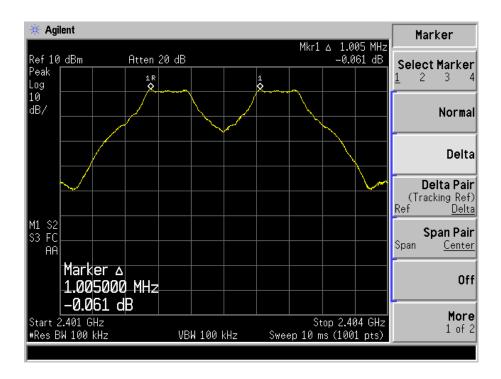
Temperature:	24 °C
Relative Humidity:	54%
ATM Pressure:	1011 mbar

6.5 Summary of Test Results/Plots

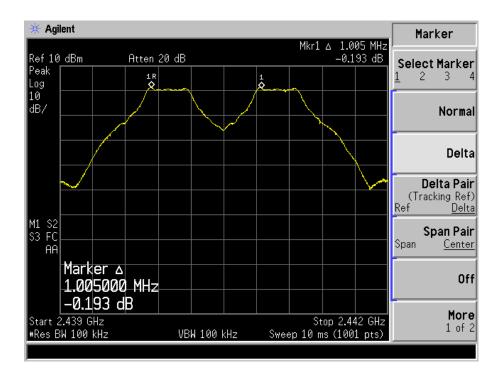




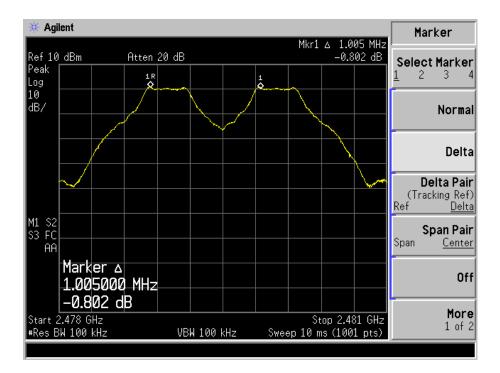
For GFSK mode Channel Spacing (Low CH=1MHz)



Channel Spacing (Middle CH=1MHz)

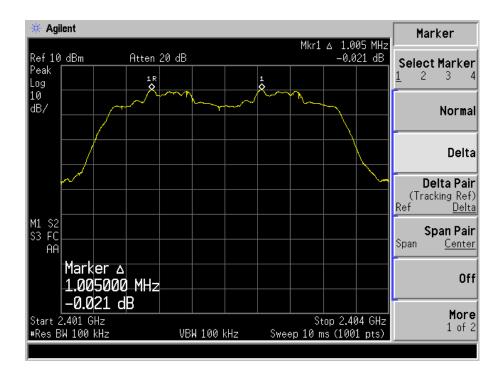


Channel Spacing (High CH=1MHz)

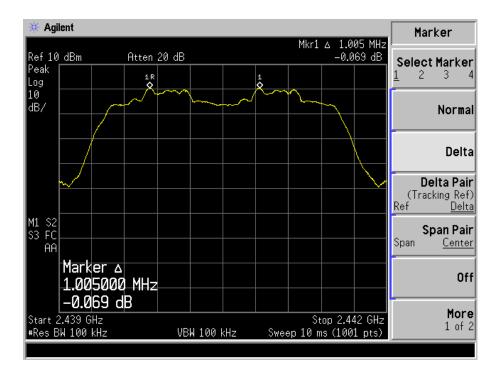


For 8DPSK mode

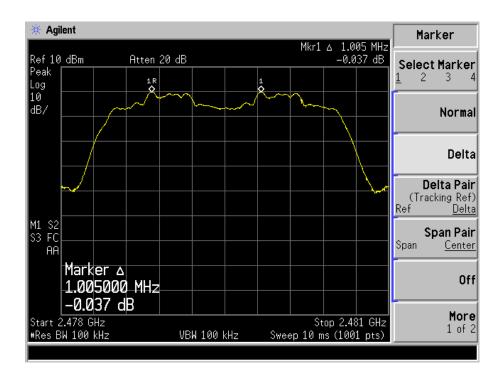
Channel Spacing (Low CH=1MHz)



Channel Spacing (Middle CH=1MHz)



Channel Spacing (High CH=1MHz)



7. Dwell Time of Hopping Channel

7.1 Standard Applicable

According to 15.247(a)(1)(iii), Frequency hopping systems in the 2400–2483.5 MHz band shall use at least 15 channels. The average time of occupancy on any channel shall not be greater than 0.4 seconds within a period of 0.4 seconds multiplied by the number of hopping channels employed.

7.2 Test Equipment List and Details

Description	Manufacturer	Model	Serial Number	Cal. Date	Due. Date
Spectrum Analyzer	Agilent	E4402B	US41192821	2015-05-28	2016-05-27
Attenuator	ATTEN	ATS100-4-20	/	2015-05-28	2016-05-27

7.3 Test Procedure

According to the DA 00-705, the dwell time of a hopping channel test method as follows.

Remove the antenna from the EUT and then connect a low loss RF cable from the antenna port to the spectrum analyzer.

Set span = zero span, centered on a hopping channel RBW = 1MHz, VBW = 1MHz Sweep = auto Detector function = peak Trace = max hold Use the marker-delta function to determine the dwell time

7.4 Environmental Conditions

Temperature:	24 °C
Relative Humidity:	54%
ATM Pressure:	1011 mbar

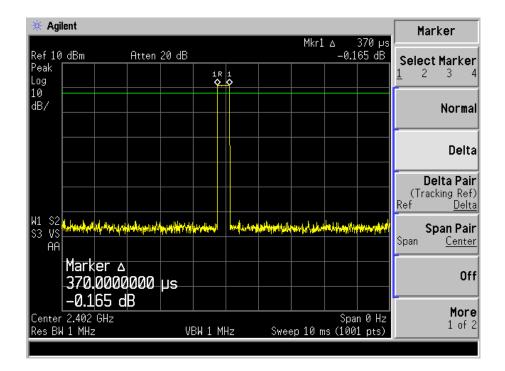
7.5 Summary of Test Results/Plots

The dwell time within a period in data mode is independent from the packet type (packet length). Test data is corrected with the worse case, which the packet length is DH1, DH3, and DH5.

The test period: T = 0.4 Second * 79 Channel = 31.6 s Dwell time = time slot length * (1600/79) * Period/N (N=2 which DH1, 2DH1, 3DH1, 4 which DH3, 2DH3, 3DH3, 6 which DH5, 2DH5, 3DH5)

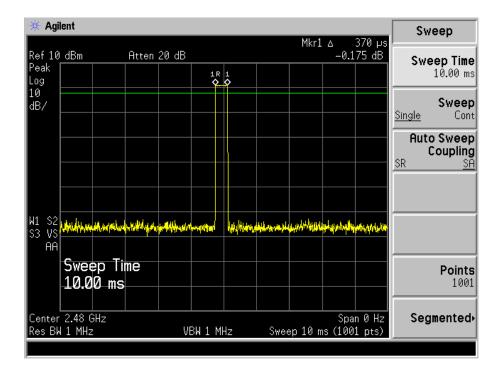
		D. 1.4	Time Slot Length	Dwell Time	Limit
Modulation	Test Channel	Packet	ms	ms	ms
		DH1	0.370	118.400	400
	2402MHz	DH3	1.620	259.200	400
		DH5	2.870	306.133	400
		DH1	0.370	118.400	400
GFSK	2441MHz	DH3	1.620	259.200	400
		DH5	2.870	306.133	400
		DH1	0.370	118.400	400
	2480MHz	DH3	1.620	259.200	400
		DH5	2.870	306.133	400
		3DH1	0.380	121.600	400
	2402MHz	3DH3	1.620	259.200	400
		3DH5	2.870	306.133	400
		3DH1	0.380	121.600	400
8DPSK	2441MHz	3DH3	1.620	259.200	400
		3DH5	2.870	306.133	400
		3DH1	0.380	121.600	400
	2480MHz	3DH3	1.620	259.200	400
		3DH5	2.870	306.133	400

Please refer to the test plots as below:

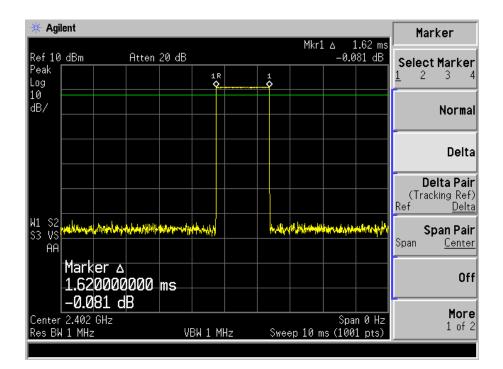


DH1 time slot (Low, Middle, High Channels)

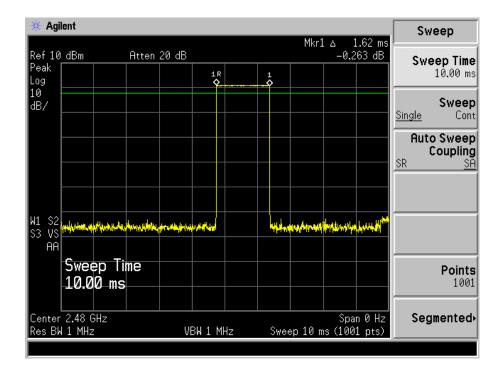
🔆 Agil	lent								Mice 1		270	Sweep
Ref 10 Peak	dBm		Atten	20 dB		- 4			Mkr1		370 µs ∂.214 dB	Sweep Time 10.00 ms
Log 10 dB/						R 1	>					Sweet Single Con
												Auto Sweep Coupling SR Sf
W1 S2 S3 VS AA	a the second	nd felinget	let the second	anatri, 4141	ndedana)		nde a hear thick	****	n/hithirthic	wysię, "dęd	hhimmin an	
	Swee 10.0											Points 1001
	2.441 1 MHz	GHz		V	BW 1	MH:	z	Swe	ep 10 m		pan 0 Hz 001 pts)	Segmented



DH3 time slot (Low, Middle, High Channels)

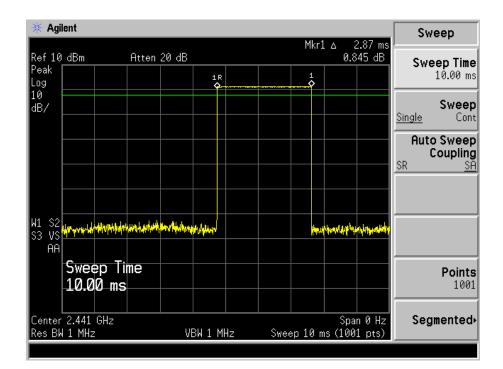


🔆 Agilent						Sweep
Ref 10 dBm	Atten 20	dB			1.62 ms).03 dB	Sweep Time
Peak Log		1 R •				10.00 ms
10 dB/						Sweep Single Cont
						Auto Sweep Coupling SR <u>SA</u>
U1 00						
W1 S2 S3 VS AA	nundah béhi béhir di saka/	antalaya saryi		₩₩₩₩₩₩₩₩₩₩₩₩	adartar da f	
Sweep 10.00	Time ms					Points 1001
Center 2.441 GH Res BW 1 MHz	lz	VBW 1 MHz	Sweep	Sp: 10 ms (100	an 0 Hz 01 pts)	Segmented



Marker										lent	🔆 Agi
Select Marke	2.87 ms 589 dB		Mkr1				20 dB	Atten		dBm	Ref 10
<u>1</u> 2 3						1 R					Peak Log
Norma											10 dB/
Delta											
Delta Pai (Tracking Ref Ref Delt											
Span Pai Span <u>Cente</u>	ndffadrædaveder	hallwale', began	ert41			anvente	lothet to the	it washing the	lan di na fata di lan	walana ka	√1 S2 S3 VS AA
Of							ms		(er ∆ 70000 89 dl	2.87	
More 1 of	an 0 Hz 01 pts)		p 10 m	Swe	IHz	BW 1 M	VI		GHz	2.402 1 MHz	

DH5 time slot (Low, Middle, High Channels)

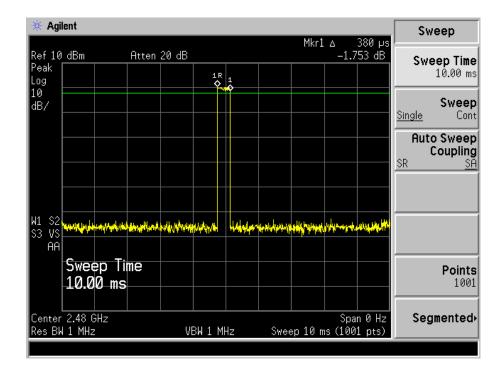


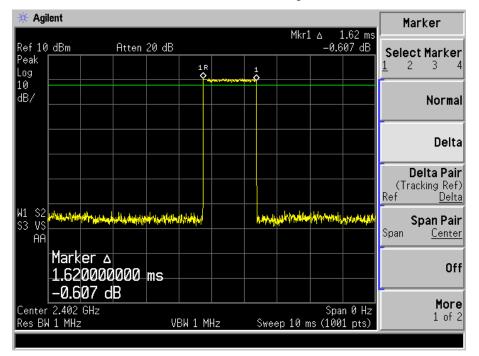
🔆 Agilent					Sweep
Ref 10_dBm	Atten 20 dB		Mkr1 ∆	2.87 ms 0.567 dB	Sweep Time
Peak Log		1 R			10.00 ms
10 dB/					Sweep Single Cont
					Auto Sweep Coupling SR <u>Sf</u>
W1 S2 datas a jar de as					
W1 S2 S3 VS AA	***		in the second	****	
Sweep 10.00 m					Points 100
Center 2.48 GHz Res BW 1 MHz		BW 1 MHz	S Sweep 10 ms (1	pan 0 Hz 001 pts)	Segmented

3DH1 time slot (Low, Middle, High Channels)

🔆 Agil	lent											Marker
Ref 10	dBm		Atten	20 dB					Mkr1		380 µs .618 dB	Select Marker
Peak _og												<u>1</u> 2 3 4
10 dB/												Norma
												Delta
												Delta Pai (Tracking Ref Ref Delt
W1 S2 S3 VS AA	hirlyne, hie	kala da kala d Kala da kala da	,r,JHrithday	dapat Applebold			ne tyldydd	mmunuale	nte hytety	he teek be	hatta da an	Span Pai Span <u>Cente</u>
	Mark 380.		000	μs								Of
	2.402	GHz	D	V	 BW 1	 MH:	 z	Swee	ep 10 m		an 0 Hz 01 pts)	More 1 of 2

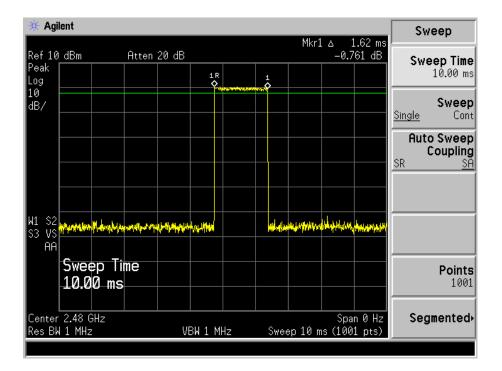
🔆 Agilent			kal 4 -	200	Sweep
Ref 10 dBm	Atten 20 dl		Mkr1 ∆	380 µs −1.128 dB	Sweep Time
Peak					10.00 ms
10 dB/					Sweep Single Cont
					Auto Sweep Coupling SR SF
					<u>on or</u>
41 S2 53 VS	waathy and yaathy aaa haalaad	Adamanyana histoodalay	tobleheltenguistenet mi	What mode projecticity and	
AA Sweep 10.00					Points 1001
Center 2.441 GHz Res BW 1 MHz		VBW 1 MHz	Sweep 10 ms	Span 0 Hz (1001 pts)	Segmented



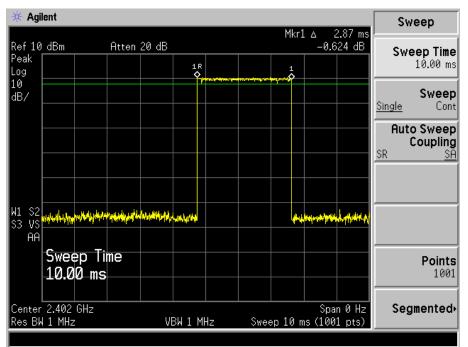


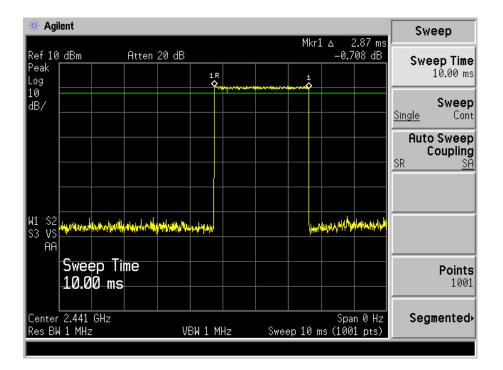


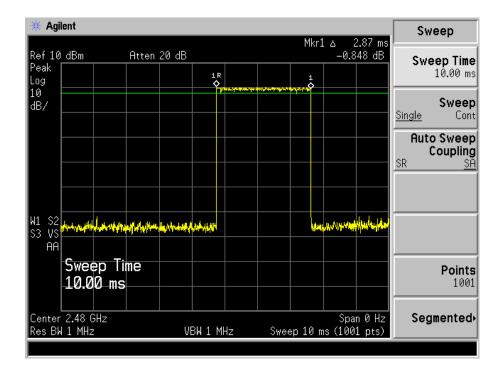
🔆 Agil	lent										Sweep
Ref 10	dBm		Atten	20 dB				Mkr1		1.62 ms 31 dB	Sweep Time
eak .og					1 R						10.00 m
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											Auto Swee Couplin SR S
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	Swee 10.0	ep Ti Ø ms	me								Point 100
	2.441 1 MHz			VI	 3wi1 M	 Hz	Swee	ep 10 m		n 0 Hz 1 pts)	Segmented



3DH5 time slot (Low, Middle, High Channels)







8. 20dB Bandwidth

8.1 Standard Applicable

According to 15.247(a)(1)(iii). For frequency hopping systems operating in the 2400MHz-2483.5 MHz no limit for 20dB bandwidth.

8.2 Test Equipment List and Details

Description	Manufacturer	Model	Serial Number	Cal. Date	Due. Date
Spectrum Analyzer	Agilent	E4402B	US41192821	2015-05-28	2016-05-27
Attenuator	ATTEN	ATS100-4-20	/	2015-05-28	2016-05-27

8.3 Test Procedure

According to the DA 00-705, the 20dB bandwidth test method as follows.

Remove the antenna from the EUT and then connect a low loss RF cable from the antenna port to the spectrum analyzer.

Span = approximately 2 to 3 times the 20 dB bandwidth, centered on a hopping channel

RBW $\geq 1\%$ of the 20 dB bandwidth

 $VBW \ge RBW$

Sweep = auto; Detector function = peak

Trace = max hold

All the trace to stabilize, use the marker-to-peak function to set the marker to the peak of the emission, use the marker-delta function to measure and record the 20dB down bandwidth of the emission.

8.4 Environmental Conditions

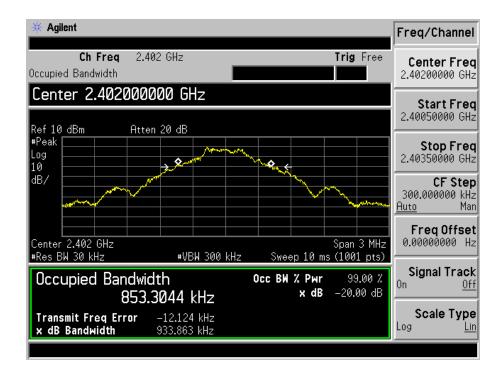
Temperature:	25 °C
Relative Humidity:	53%
ATM Pressure:	1018 mbar

8.5 Summary of Test Results/Plots

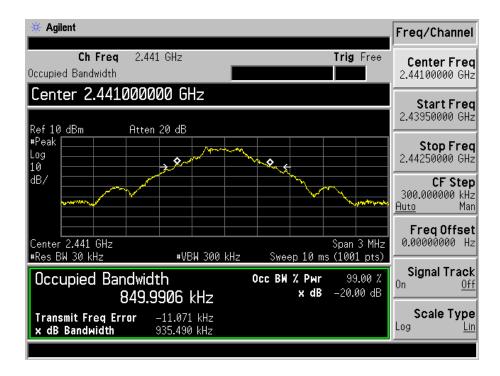
Test Mode	Test Channel	20 dB Bandwidth	99% Bandwidth	Limit
Test Widde	MHz	kHz	kHz	kHz
	2402	933.863	853.3044	
GFSK	2441	935.490	849.9906	
	2480	938.789	858.0466	
	2402	1264	1163.6	
8DPSK	2441	1270	1160.8	
	2480	1272	1158.3	

For GFSK

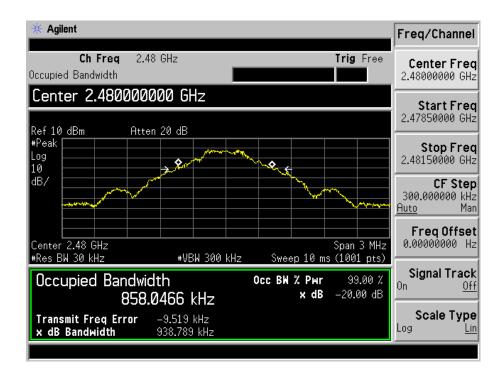
Low Channel:



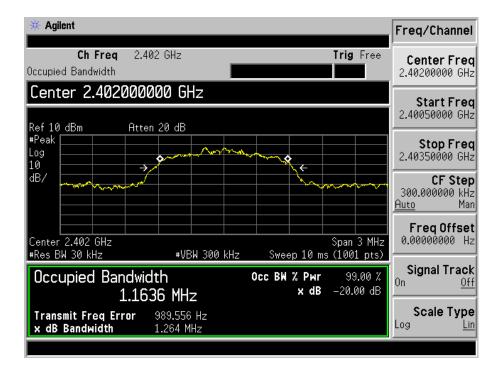
Middle Channel:



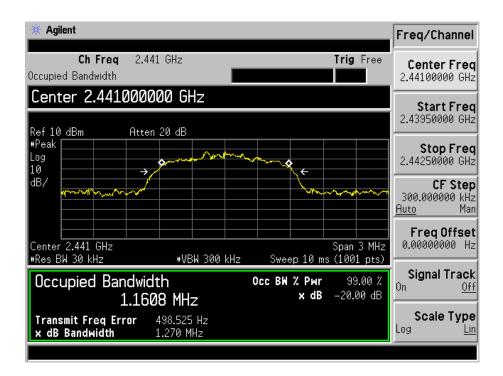
High Channel:



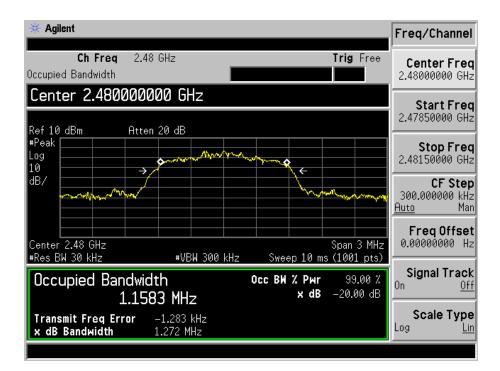
For 8DPSK Low Channel:



Middle Channel:



High Channel:



9. RF Output Power

9.1 Standard Applicable

According to 15.247(b)(1). For frequency hopping systems operating in the 2400–2483.5 MHz band employing at least 75 non-overlapping hopping channels, and all frequency hopping systems in the 5725–5850 MHz band: 1 watt. For all other frequency hopping systems in the 2400–2483.5 MHz band: 0.125 watts.

9.2 Test Equipment List and Details

Description	Manufacturer	Model	Serial Number	Cal. Date	Due. Date
Spectrum Analyzer	Agilent	E4402B	US41192821	2015-05-28	2016-05-27
Attenuator	ATTEN	ATS100-4-20	/	2015-05-28	2016-05-27

9.3 Test Procedure

According to the DA 00-705, the peak output power test method as follows.

Remove the antenna from the EUT and then connect a low loss RF cable from the antenna port to the spectrum analyzer.

Span = approximately 5 times the 20 dB bandwidth, centered on a hopping channel

RBW > the 20 dB bandwidth of the emission being measured

 $VBW \ge RBW$

Sweep = auto

Detector function = peak

Trace = max hold

All the trace to stabilize, use the marker-to-peak function to set the marker to the peak of the emission, the indicated level is the peak output power (the external attenuation and cable loss shall be considered).

9.4 Environmental Conditions

Temperature:	24 °C
Relative Humidity:	55%
ATM Pressure:	1011 mbar

9.5 Summary of Test Results/Plots

Channel	Frequency MHz	Measured Value dBm	Output Power mW	Limit mW
Low Channel	2402	1.058	1.276	1000
Middle Channel	2441	1.364	1.369	1000
High Channel	2480	1.329	1.358	1000

For Pi/4 QDPSK

Channel	Frequency	Measured Value	Output Power	Limit
Chaimer	MHz	dBm	mW	mW
Low Channel	2402	0.464	1.113	1000
Middle Channel	2441	0.560	1.138	1000
High Channel	2480	0.445	1.108	1000

For 8DPSK

Channel	Frequency	Measured Value	Output Power	Limit
Channel	MHz	dBm	mW	mW
Low Channel	2402	0.525	1.128	1000
Middle Channel	2441	0.845	1.215	1000
High Channel	2480	0.323	1.077	1000

Note: the antenna gain of 1.9dBi less than 6dBi maximum permission antenna gain value based on 1 watt peak output power limit.

10. Field Strength of Spurious Emissions

10.1 Measurement Uncertainty

Based on NIS 81, The Treatment of Uncertainty in EMC Measurements, the best estimate of the uncertainty of a radiation emissions measurement is ± 5.10 dB.

10.2 Standard Applicable

According to §15.247(d), in any 100 kHz bandwidth outside the frequency band in which the spread spectrum or digitally modulated intentional radiator is operating, the radio frequency power that is produced by the intentional radiator shall be at least 20 dB below that in the 100 kHz bandwidth within the band that contains the highest level of the desired power, based on either an RF conducted or a radiated measurement, provided the transmitter demonstrates compliance with the peak conducted power limits. If the transmitter complies with the conducted power limits based on the use of RMS averaging over a time interval, as permitted under paragraph (b)(3) of this section, the attenuation required under this paragraph shall be 30 dB instead of 20 dB. Attenuation below the general limits specified in §15.209(a) is not required. In addition, radiated emissions which fall in the restricted bands, as defined in §15.209(a), must also comply with the radiated emission limits specified in §15.209(a).

The emission limit in this paragraph is based on measurement instrumentation employing an average detector. The provisions in §15.35 for limiting peak emissions apply. Spurious Radiated Emissions measurements starting below or at the lowest crystal frequency.

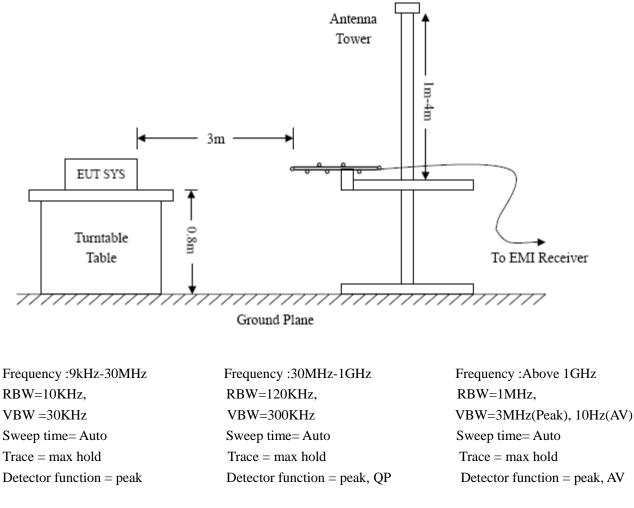
Description	Manufacturer	Model	Serial Number	Cal. Date	Due. Date
Spectrum Analyzer	R&S	FSP	836079/035	2015-05-28	2016-05-27
EMI Test Receiver	R&S	ESVB	825471/005	2015-05-28	2016-05-27
Pre-amplifier	Agilent	8447F	3113A06717	2015-05-28	2016-05-27
Pre-amplifier	Compliance Direction	PAP-0118	24002	2015-05-28	2016-05-27
Trilog Broadband Antenna	SCHWARZBECK	VULB9163	9163-333	2015-05-24	2016-05-23
Horn Antenna	ETS	3117	00086197	2015-05-24	2016-05-23
Horn Antenna	ETS	3116B	00088203	2015-05-24	2016-05-23
Loop Antenna	SCHWARZECK	HFRA 5165	9365	2015-05-24	2016-05-23

10.3 Test Equipment List and Details

10.4 Test Procedure

The setup of EUT is according with per ANSI C63.4-2009 measurement procedure. The specification used was with the FCC Part 15.205 15.247(a) and FCC Part 15.209 Limit.

The external I/O cables were draped along the test table and formed a bundle 30 to 40 cm long in the middle. The spacing between the peripherals was 10 cm.



10.5 Corrected Amplitude & Margin Calculation

The Corrected Amplitude is calculated by adding the Antenna Factor and the Cable Factor, and subtracting the Amplifier Gain from the Amplitude reading. The basic equation is as follows:

Corr. Ampl. = Indicated Reading + Ant. Factor + Cable Loss - Ampl. Gain

The "**Margin**" column of the following data tables indicates the degree of compliance with the applicable limit. For example, a margin of $-6dB\mu V$ means the emission is $6dB\mu V$ below the maximum limit for Class B. The equation for margin calculation is as follows:

Margin = Corr. Ampl. – FCC Part 15 Limit

10.6 Environmental Conditions

Temperature:	25 °C
Relative Humidity:	52%
ATM Pressure:	1012 mbar

10.7 Summary of Test Results/Plots

According to the data below, the FCC Part 15.205, 15.209 and 15.247 standards, and had the worst cases:

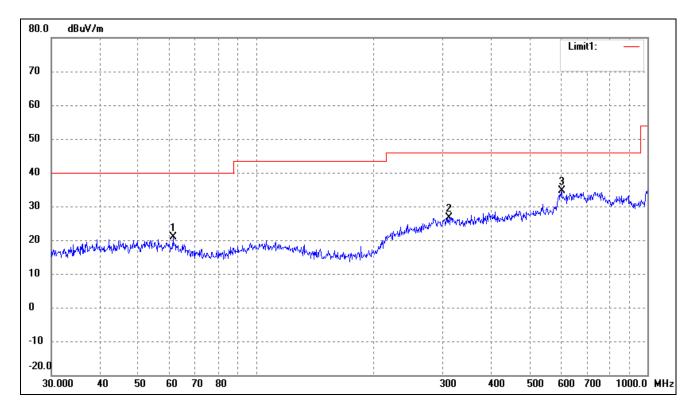
Note: this EUT was tested in 3 orthogonal positions, the **antenna horizontally** is worst case position and the data was reported.

Plot of Radiated Emissions Test Data (30MHz to 1GHz)

EUT:	Mobile Phone
Tested Model:	Q65
Operating Condition:	Transmitting Low Channel (2402MHz)
Comment:	Battery: DC3.7V

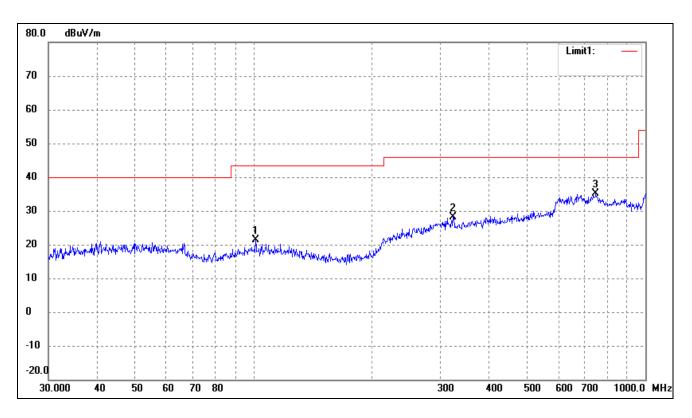
Test Specification:

Horizontal



No.	Frequency	Reading	Correct	Result	Limit	Margin	Degree	Height	Remark
	(MHz)	(dBuV/m)	Factor(dB)	(dBuV/m)	(dBuV/m)	(dB)	(°)	(cm)	
1	61.3463	15.70	5.08	20.78	40.00	-19.22	100	100	QP
2	311.0867	14.29	12.24	26.53	46.00	-19.47	150	100	QP
3	603.5392	15.45	19.06	34.51	46.00	-11.49	206	100	QP

Test Specification: Vertical

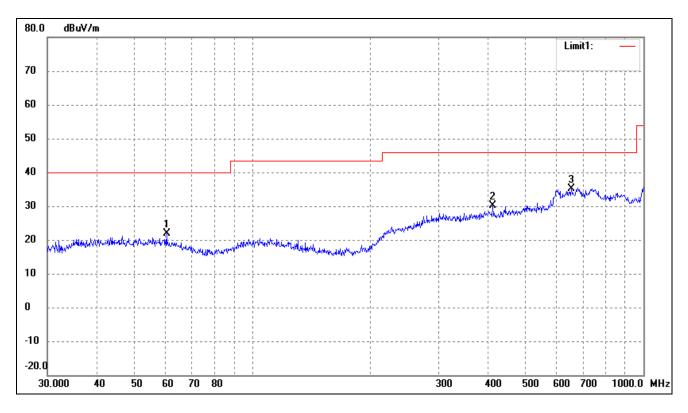


No.	Frequency	Reading	Correct	Result	Limit	Margin	Degree	Height	Remark
	(MHz)	(dBuV/m)	Factor(dB)	(dBuV/m)	(dBuV/m)	(dB)	(°)	(cm)	
1	101.2885	16.17	5.12	21.29	43.50	-22.21	145	100	QP
2	323.3204	15.83	12.19	28.02	46.00	-17.98	203	100	QP
3	747.4826	15.85	19.20	35.05	46.00	-10.95	217	100	QP

Operating Condition:	Transmitting Middle Channel (2441MHz)
Comment:	Battery: DC3.7V

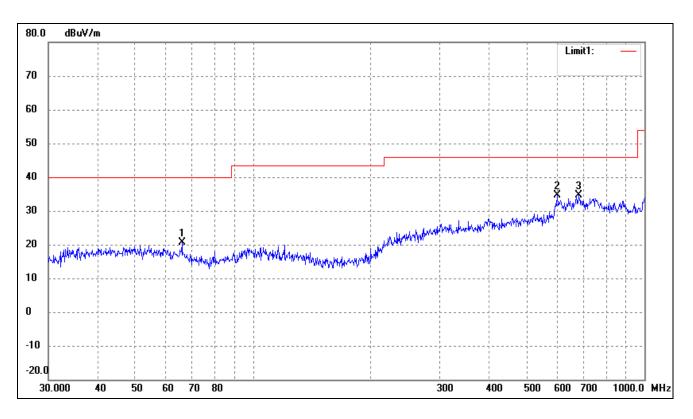
Test Specification:

Horizontal



No.	Frequency	Reading	Correct	Result	Limit	Margin	Degree	Height	Remark
	(MHz)	(dBuV/m)	Factor(dB)	(dBuV/m)	(dBuV/m)	(dB)	(°)	(cm)	
1	60.4919	16.57	5.27	21.84	40.00	-18.16	120	100	QP
2	411.8240	17.56	12.69	30.25	46.00	-15.75	124	100	QP
3	654.2318	16.76	18.27	35.03	46.00	-10.97	110	100	QP

Test Specification: Vertical

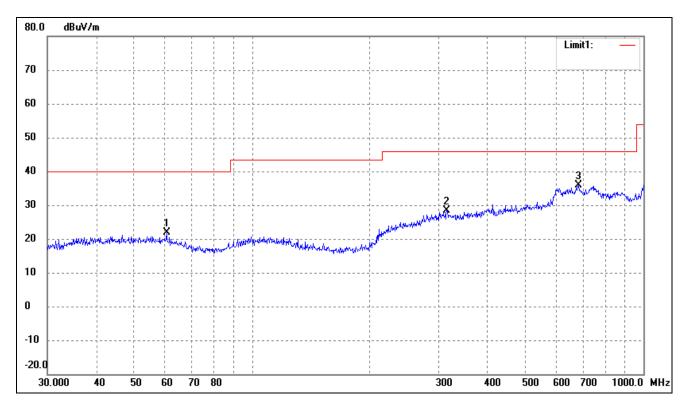


No.	Frequency	Reading	Correct	Result	Limit	Margin	Degree	Height	Remark
	(MHz)	(dBuV/m)	Factor(dB)	(dBuV/m)	(dBuV/m)	(dB)	(°)	(cm)	
1	65.8031	16.57	4.10	20.67	40.00	-19.33	360	100	QP
2	599.3213	15.32	19.19	34.51	46.00	-11.49	108	100	QP
3	679.9600	15.45	19.26	34.71	46.00	-11.29	120	100	QP

Operating Condition:	Transmitting High Channel (2480MHz)
Comment:	Battery: DC3.7V

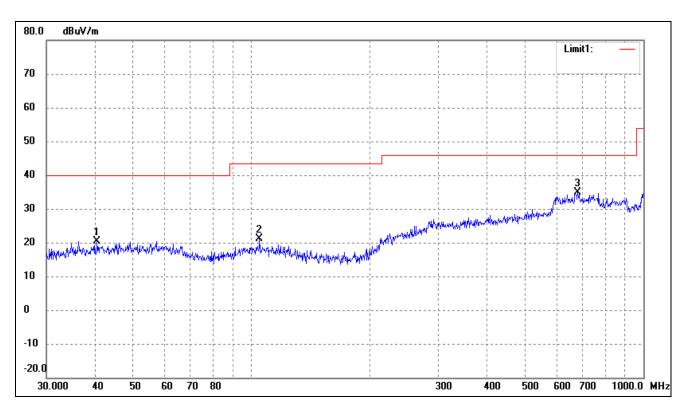
Test Specification:

Horizontal



No.	Frequency	Reading	Correct	Result	Limit	Margin	Degree	Height	Remark
	(MHz)	(dBuV/m)	dB/m	(dBuV/m)	(dBuV/m)	(dB)	(°)	(cm)	
1	60.4919	16.57	5.27	21.84	40.00	-18.16	320	100	QP
2	314.3765	16.06	12.26	28.32	46.00	-17.68	120	100	QP
3	682.3485	16.80	19.08	35.88	46.00	-10.12	224	100	QP

Test Specification: Vertical



No.	Frequency	Reading	Correct	Result	Limit	Margin	Degree	Height	Remark
	(MHz)	(dBuV/m)	dB/m	(dBuV/m)	(dBuV/m)	(dB)	(°)	(cm)	
1	40.4172	15.21	5.25	20.46	40.00	-19.54	100	100	QP
2	104.9033	15.96	5.10	21.06	43.50	-22.44	240	100	QP
3	679.9600	15.57	19.26	34.83	46.00	-11.17	360	100	QP

Frequency	Reading	Correct	Result	Limit	Margin	Polar	Detector
(MHz)	(dBuV/m)	dB/m	(dBuV/m)	(dBuV/m)	(dB)	H/V	
			Low Channe	el-2402MHz			·
4804	59.44	-3.87	55.57	74.00	-18.43	Н	РК
4804	48.47	-3.87	44.60	54.00	-9.40	Н	AV
7206	49.01	1.14	50.15	74.00	-23.85	Н	РК
7206	40.33	1.19	41.52	54.00	-12.48	Н	AV
4804	62.73	-3.86	58.87	74.00	-15.13	V	РК
4804	48.29	-3.86	44.43	54.00	-9.57	V	AV
7206	46.95	1.1	48.05	74.00	-25.95	V	РК
7206	37.48	1.1	38.58	54.00	-15.42	V	AV
			Middle Chan	nel-2441MHz			·
4882	59.63	-3.74	55.89	74.00	-18.11	Н	РК
4882	48.33	-3.74	44.59	54.00	-9.41	Н	AV
7323	52.13	1.47	53.60	74.00	-20.40	Н	РК
7323	40.59	1.47	42.06	54.00	-11.94	Н	AV
4882	68.14	-3.74	64.40	74.00	-9.60	V	РК
4882	46.44	-3.74	42.70	54.00	-11.30	V	AV
7323	51.70	1.47	53.17	74.00	-20.83	V	РК
7323	40.32	1.47	41.79	54.00	-12.21	V	AV
			High Chann	el-2480MHz			
4960	58.95	-3.59	55.36	74.00	-18.64	Н	РК
4960	47.76	-3.59	44.17	54.00	-9.83	Н	AV
7440	51.19	1.79	52.98	74.00	-21.02	Н	РК
7440	40.34	1.79	42.13	54.00	-11.87	Н	AV
4960	66.77	-3.59	63.18	74.00	-10.82	V	РК
4960	47.48	-3.59	43.89	54.00	-10.11	V	AV
7440	50.86	1.79	52.65	74.00	-21.35	V	РК
7440	40.09	1.79	41.88	54.00	-12.12	V	AV

Spurious Emissions Above 1GHz

Note: Testing is carried out with frequency rang 9kHz to the tenth harmonics, which above 3^{th} Harmonics are attenuated more than 20dB below the permissible limits or the field strength is too small to be measured. The measurements greater than 20dB below the limit from 9kHz to 30MHz.

11. Out of Band Emissions

11.1 Standard Applicable

According to §15.247 (d) In any 100 kHz bandwidth outside the frequency band in which the spread spectrum or digitally modulated intentional radiator is operating, the radio frequency power that is produced by the intentional radiator shall be at least 20 dB below that in the 100 kHz bandwidth within the band that contains the highest level of the desired power, based on either an RF conducted or a radiated measurement, provided the transmitter demonstrates compliance with the peak conducted power limits. If the transmitter complies with the conducted power limits based on the use of RMS averaging over a time interval, as permitted under paragraph (b)(3) of this section, the attenuation required under this paragraph shall be 30 dB instead of 20 dB. Attenuation below the general limits specified in §15.209(a) is not required. In addition, radiated emissions which fall in the restricted bands, as defined in §15.205(a), must also comply with the radiated emission limits specified in §15.209(a).

Description	Manufacturer	Model	Serial Number	Cal. Date	Due. Date
Spectrum Analyzer	R&S	FSP	836079/035	2015-05-28	2016-05-27
EMI Test Receiver	R&S	ESVB	825471/005	2015-05-28	2016-05-27
Pre-amplifier	Agilent	8447F	3113A06717	2015-05-28	2016-05-27
Pre-amplifier	Compliance Direction	PAP-0118	24002	2015-05-28	2016-05-27
Trilog Broadband Antenna	SCHWARZBECK	VULB9163	9163-333	2015-05-24	2016-05-23
Horn Antenna	ETS	3117	00086197	2015-05-24	2016-05-23
Spectrum Analyzer	Agilent	E4402B	US41192821	2015-05-28	2016-05-27
Attenuator	ATTEN	ATS100-4-20	/	2015-05-28	2016-05-27

11.2 Test Equipment List and Details

11.3 Test Procedure

According to the DA 00-705, the band-edge radiated test method as follows.

Set span = wide enough to capture the peak level of the emission operating on the channel closest to the bandedge, as well as any modulation products which fall outside of the authorized band of operation (2310MHz to 2410MHz for low bandedge, 2470MHz to 2500MHz for the high bandedge) RBW = 1MHz, VBW = 1MHz for peak value measured RBW = 1MHz, VBW = 10Hz for average value measured Sweep = auto; Detector function = peak; Trace = max hold

All the trace to stabilize, set the marker on the emission at the bandedge, or on the highest modulation porduct outside of the band, if this level is greater than that at the bandedge. Enable the marker-delta function, then use the marker-to-peak function to move the marker to the peak of the in-band emission. Those emission must comply with the 15.209 limit for fall in the restricted bands listed in section 15.205. Note that the method of measurement KDB publication number: 913591 may be used for the radiated bandedge measurements.

According to the DA 00-705, the band-edge conducted test method as follows:

Set span = wide enough to capture the peak level of the emission operating on the channel closest to the bandedge, as well as any modulation products which fall outside of the authorized band of operation (2380MHz to 2410MHz for low bandedge, 2470MHz to 2500MHz for the high bandedge) RBW = 100kHz, VBW = 300kHz Sweep = auto; Detector function = peak; Trace = max hold

All the trace to stabilize, set the marker on the emission at the bandedge, or on the highest modulation porduct outside of the band, if this level is greater than that at the bandedge. Enable the marker-delta function, then use the marker-to-peak function to move the marker to the peak of the in-band emission. Those emission must comply with the limit specified in this section (at least 20dB attenuation).

11.4 Environmental Conditions

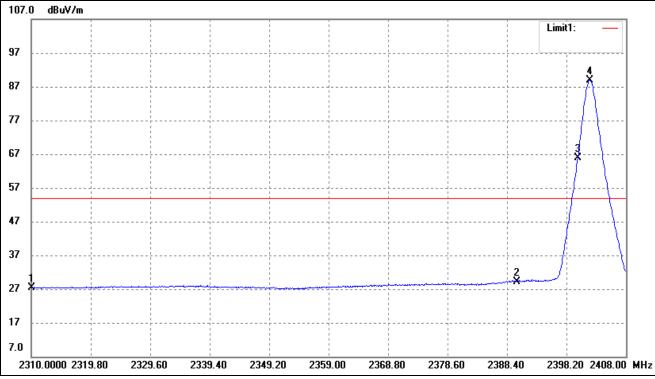
Temperature:	23°C
Relative Humidity:	54%
ATM Pressure:	1011 mbar

11.5 Summary of Test Results/Plots

Please refer to the test plots as below.

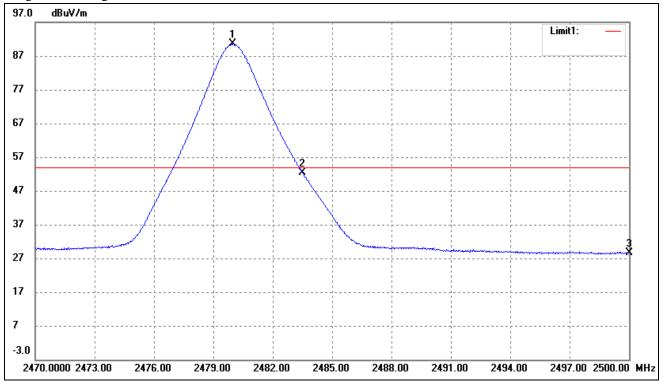
Bandedge (Radiated)

Lowest Bandedge



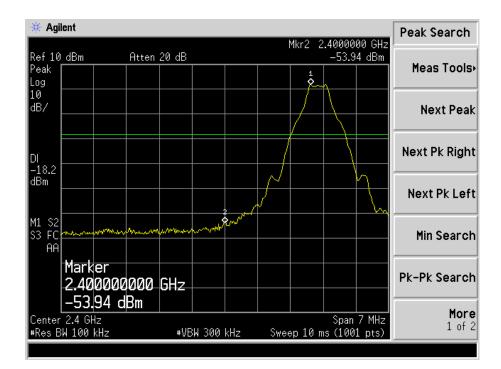
No.	Frequency	Reading	Correct	Result	Limit Margin		Remark
	(MHz)	(dBuV/m)	Factor(dB)	(dBuV/m)	(dBuV/m) (dB)		
1	2310.000	31.11	-3.71	27.40	54.00 -26.60		Average Detector
	2310.000	42.90	-3.71	39.19	74.00 -34.81		Peak Detector
2	2390.000	32.74	-3.54	29.20	54.00 -24.80		Average Detector
	2390.000	44.03	-3.54	40.49	74.00 -33.51		Peak Detector
3	2400.000	69.47	-3.51	65.96	Delta = 23.04 dBc		Average Detector
4	2402.022	92.51	-3.51	89.00	Delta = 2 .	0.04uDC	Average Detector

Highest Bandedge



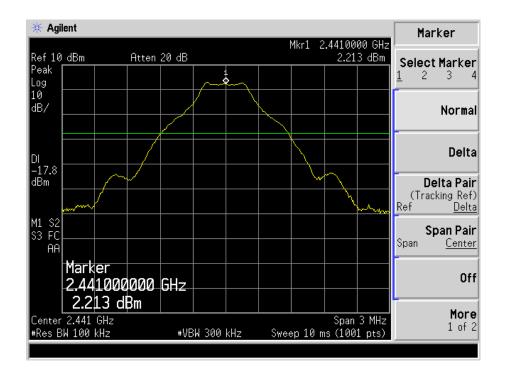
No.	Frequency	Reading	Correct	Result	Limit	Margin	Remark
	(MHz)	(dBuV/m)	Factor(dB)	(dBuV/m)	(dBuV/m)	(dB)	
1	2479.960	93.86	-3.33	90.53	/	/	Average Detector
	2480.110	100.63	-3.33	97.30	/	/	Peak Detector
2	2483.500	55.79	-3.33	52.46	54.00	-1.54	Average Detector
	2483.500	61.21	-3.33	57.88	74.00	-16.12	Peak Detector
3	2500.000	31.84	-3.28	28.56	54.00	-25.44	Average Detector
	2500.000	43.54	-3.28	40.26	74.00	-33.74	Peak Detector

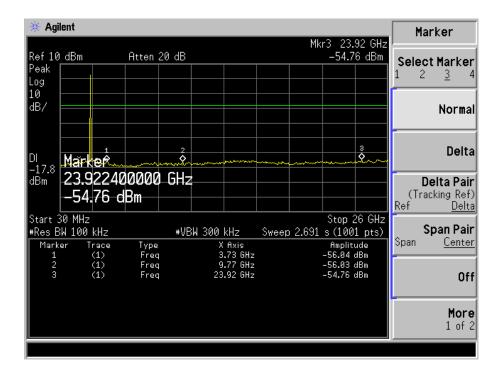
Bandedge (Conducted) Low Channel



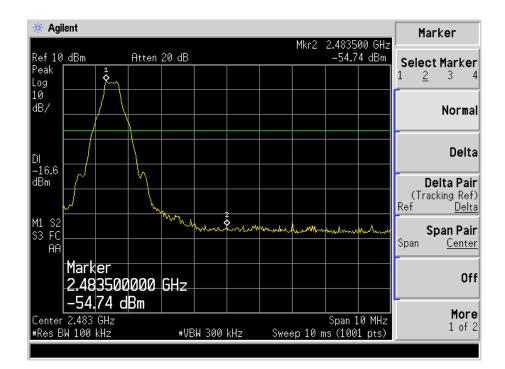
🔆 Agi	lent							ه ديراله	64 CU-	Ma	arker
Ref 10 Peak Log 10 dB/	dBm		Atten	20 dB					64 GHz 18 dBm	Selec 1 2	t Marker <u>3</u> 4 Normal
	9.63	ter \$ 8900 .08 d	000							-	Delta Delta Pair acking Ref) Delta
Start 3 #Res B Mark 1 2 3	W 100 er 1		Type Frec Frec Frec		KHz X Axis 4.83 GH: 7.56 GH: 9.64 GH:	z z	2.691	Stop s (100) Amplit -56.04 -56.59 -52.08	ude dBm dBm		Span Pair Center Off
C+\\$1	ATE26	9.STA	file sa	ved							More 1 of 2

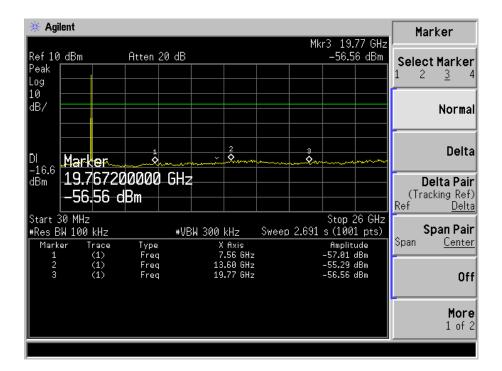
Middle Channel



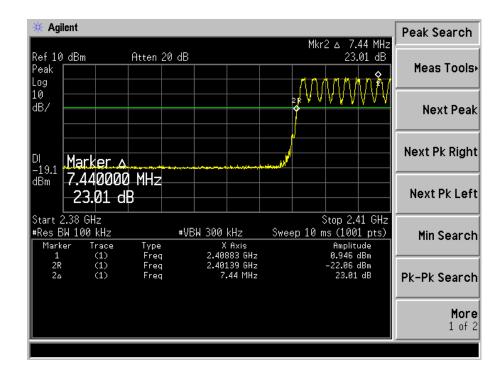


High Channel

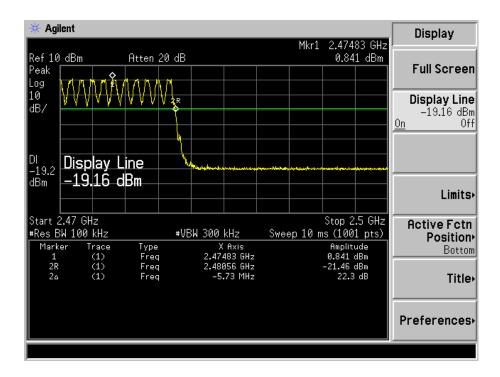




Bandedge (Conducted) Lowest Bandedge



Highest Bandedge



12. Conducted Emissions

12.1 Measurement Uncertainty

Base on NIS 81, The Treatment of Uncertainty in EMC Measurements, the best estimate of the uncertainty of any conducted emissions measurement is \pm 2.88 dB.

12.2 Test Equipment List and Details

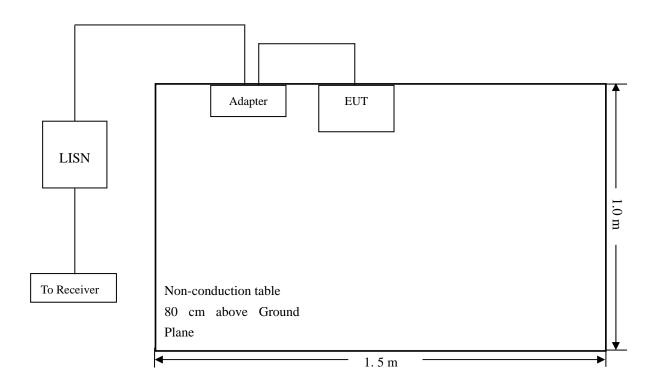
Description	Manufacturer	Model	Serial Number	Cal. Date	Due. Date
EMI Test Receiver	Rohde & Schwarz	ESPI	101611	2015-05-28	2016-05-27
L.I.S.N	Schwarz beck	NSLK8126	8126-224	2015-05-28	2016-05-27
Pulse Limiter	Rohde & Schwarz	ESH3-Z2	100911	2015-05-28	2016-05-27

12.3 Test Procedure

The setup of EUT is according with per ANSI C63.4-2009 measurement procedure. The specification used was with the FCC Part 15.207 Limit.

The external I/O cables were draped along the test table and formed a bundle 30 to 40 cm long in the middle. The spacing between the peripherals was 10 cm.

12.4 Basic Test Setup Block Diagram



12.5 Environmental Conditions

Temperature:	25 °C
Relative Humidity:	52%
ATM Pressure:	1012 mbar

12.6 Test Receiver Setup

During the conducted emission test, the test receiver was set with the following configurations:

Start Frequency	150 kHz
Stop Frequency	30 MHz
Sweep Speed	Auto
IF Bandwidth	10 kHz
Quasi-Peak Adapter Bandwidth	9 kHz
Quasi-Peak Adapter Mode	Normal

12.7 Summary of Test Results/Plots

According to the data in section 12.8, the EUT <u>complied with the FCC Part 15.207</u> Conducted margin for a Class B device, with the *worst* margin reading of:

-4.77dB at 0.5980 MHz in the Line, QP detector, 0.15-30MHz

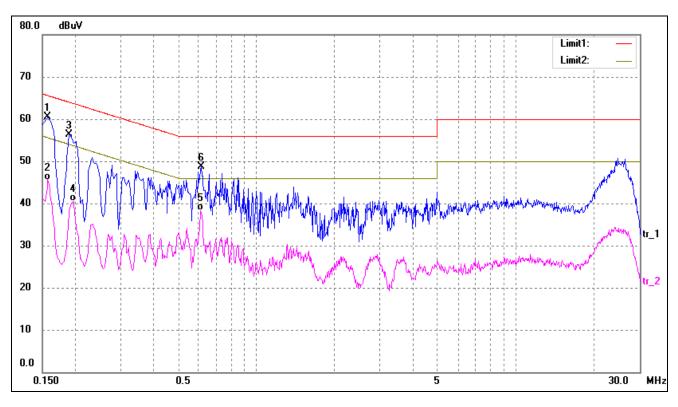
12.8 Conducted Emissions Test Data

Plot of Conducted Emissions Test Data

EUT:	Mobile Phone
Tested Model:	Q65
Operating Condition:	(BT)Transmitting
Comment:	AC 120V/60Hz

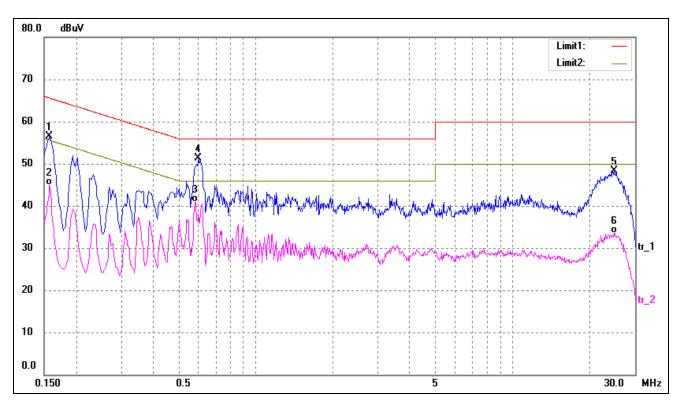
Test Specification:

Neutral



No.	Frequency	Reading	Correct	Result	Limit	Margin	Detector
	(MHz)	(dBuV)	(dB/m)	(dBuV)	(dBuV)	(dB)	
1	0.1580	47.97	12.50	60.47	65.57	-5.10	QP
2	0.1580	33.10	12.50	45.60	55.57	-9.97	AVG
3	0.1904	43.85	12.50	56.35	64.02	-7.67	QP
4	0.1980	28.09	12.50	40.59	53.69	-13.10	AVG
5	0.6100	25.76	12.61	38.37	46.00	-7.63	AVG
6	0.6140	36.04	12.61	48.65	56.00	-7.35	QP

Test Specification: Line



No.	Frequency	Reading	Correct	Result	Limit	Margin	Detector
	(MHz)	(dBuV)	(dB/m)	(dBuV)	(dBuV)	(dB)	
1	0.1580	44.03	12.50	56.53	65.57	-9.04	QP
2	0.1580	32.44	12.50	44.94	55.57	-10.63	AVG
3	0.5820	28.38	12.58	40.96	46.00	-5.04	AVG
4	0.5980	38.63	12.60	51.23	56.00	-4.77	QP
5	24.8660	35.30	12.96	48.26	60.00	-11.74	QP
6	24.8660	20.52	12.96	33.48	50.00	-16.52	AVG

***** END OF REPORT *****